

# Influence of Feedback Parameters on Resistance Control of Metal Nanowires by Stepwise Feedback-Controlled Electromigration

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## Introduction

- Fast Progress and Development of Nanoelectronics
  - Intensive Studies in Fundamental Physical Properties of Metallic Nanogaps [1]
- Electromigration Method for the Fabrication of Nanogaps
  - Simple Method Achieved by Only Passing a Current Through a Metal Nanowire [2]
  - Feedback-Controlled Electromigration (FCE) [3,4]

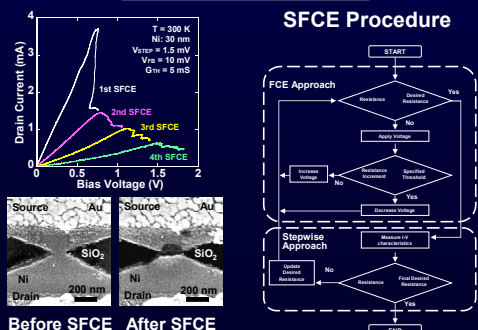
[1] K. I. Bolotin, et al., Nano Lett. 5 1685 (2005).  
[2] H. Park, et al., Appl. Phys. Lett. 75 301(1999).

[3] D. R. Strachan, et al., Appl. Phys. Lett. 86 43109 (2005).  
[4] K. Takahashi, et al., J. Vac. Sci. Technol. B 27 805 (2009).

## A New Approach to Control The Resistance of Metal Nanowires @ Room Temperature

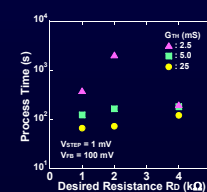
## Resistance Control by Stepwise Feedback-Controlled Electromigration (SFCE)

### SFCE Scheme

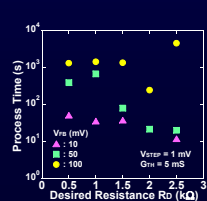


### Optimization of Feedback Parameters

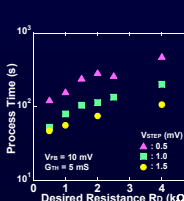
#### Threshold Differential Conductance $G_{TH}$



#### Feedback Voltage $V_{FB}$



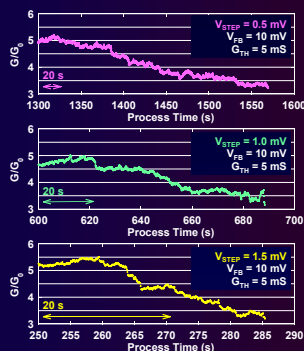
#### Voltage Step $V_{STEP}$



Decrease of Process Time

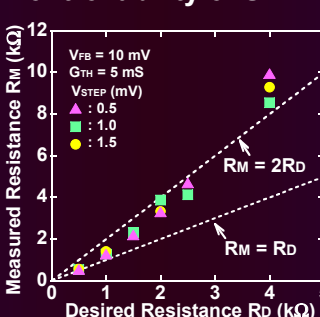
## Resistance Control Using SFCE with Optimized Feedback Parameters

### Conductance Trace



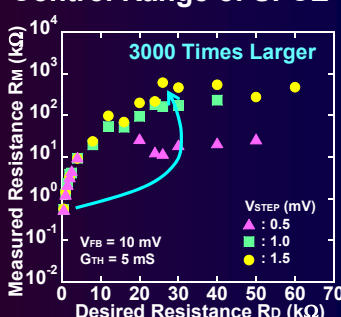
Stable Formation of QPC  
(Quantum Point Contact)

### Controllability of SFCE



$R_D < 20 \text{ k}$  : No Influence of  $V_{STEP}$  on the Channel Resistance  
 $R_D \geq 20 \text{ k}$  : Formation of Tunnel Junction

### Control Range of SFCE



## High-Speed, Stable, and Wide-Range Control of Channel Resistance Using SFCE

## Conclusions

- Control of Channel Resistance of Metal Nanowires Using SFCE Process
  - Successful Resistance Control by Suppression of Excess Heating During Electromigration
- Optimization of Feedback Parameters of SFCE Scheme
  - Considerable Decrease of the Process Time of the SFCE Procedure
- Resistance Control Using SFCE with Optimized Feedback Parameters
  - No Degradation of the Controllability of the SFCE by Increase of  $V_{STEP}$
  - Decrease of Process Time of SFCE Procedure in QPC Regime
  - Resistance Control from 200 (Metallic Regime) to 600 k (Tunneling Regime) for 20 Min